Declaration page 1 of 2 10/631,328

DOCKET NO. 00-253/1D 81605(6653)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): NAGARAJAN, Kumar

et al.

Serial No.: 10/631,328

Filed: July 30, 2003

For: BALANCED COEFFICIENT OF

EXPANSION FOR FLIP CHIP

BALL GRID ARRAY

Art Unit: 2824

Examiner: Smith, Bradley K.

CERTIFICATE OF TRANSMISSION/MAILING

I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:

Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 or the date below.

110 23 2004 NOUNT

Rhonda L. Mason

DECLARATION UNDER 37 C.F.R. § 1.131

We, KUMAR NAGARAJAN, ZAFER KUTLU and SHIRISH SHAH, hereby declare as follows:

- 1. We are the co-inventors of the invention disclosed and claimed in the subject application, which is a divisional of Serial No. 09/680,759, now U.S. Patent 6,639,321 B1;
- 2. We submitted a copy of the invention disclosure attached hereto for "CTE BALANCED FLIP CHIP BGA" to LSI Logic Corporation before the filing date of August 30, 2000, of U.S. Patent 6,441,499 B1 by Nagarajan, et al.;
 - 3. We conceived the invention disclosed in the

Declaration page 2 of 10/631,328

DOCKET NO. 00-253/1D 81605(6653)

attached invention disclosure in the United States of America;

4. The undersigned further declare that all statements made herein of our own knowledge are true; and that all statements not based on our own knowledge are believed to be true; and further that these statements were made with the knowledge that willful false statements are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code.

/s/	المستشلا
DATE 5/24/04	SIGNATURE
	KUMAR NAGARAJAN
/s/	
DATE	SIGNATURE
	ZAFER KUTLU
/s/	
DATE	SIGNATURE

SHIRISH SHAH

Declaration page 1 of 2 10/631,328

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the United States Code.

/s/	
DATE	SIGNATURE

KUMAR NAGARAJAN

DATE SIGNATURE

5/25/04

ZAFER KUTLU

DATE SIGNATURE SHIRLSH SHAH

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	LS	TOGIC - INVEN, ON DISCLOSURE FORM	Disclosure No. P-
1. *	INVE	NTOR(S)	
ļ	A.	NAMÉ: Kumar Nagarajan WS - F124	EXT. 7317
		HOME	HOME PHONE: 408-428-0893
]			CITIZENSHIP: India
	В.	NAME: Zafer Kuttu MS F-124	EXT. 7020
	C.	HOME ADDRESS: 1230 Middle Ave., Menio Park, CA 94305	HOME PHONE: 650-322-7545 Clizenship: USA
	J	NAMB: Shirish Shah M/S - F-124	EXT: 8331 Home Phone: 510-494-0886
	<u> </u>	HOME ADDRESS: 5727 Oleander Common, Framont, CA 94555	CITIZENSHIP: India
	Ð.	DIVISION, DEPARTMENT, SUBSIDIARY: ADVANCED PROCESS DEVELOPMENT	
		DIFFECTOR: John McCormick /Ed Fulcher	VICE PRESIDENT: Manlam Alagaratram
2	, mal	OF THE INVENTION	
<u></u>		BE FILEU OUT) CTE Balenced Filp Chip BGA	
3.	CONC	EPTION OF THE INVENTION	
	Α.	DATE OF FIRST DRAWING	3/18/00
		WHERE CAN FIRST DRAWING BE FOUND?	Enggr
	B.	DATE OF FIRST WRITTEN DESCRIPTION	3/18/00
	<u> </u>	WHERE IS DESCRIPTION FOUND?	
	c.	DATE OF FIRST CRAL DISCLOSURE TO OTHERS	3/15/00
		TO WHOM?	
4.	CONS	TRUCTION OF DEVICE	
	A.	DATE COMPLETED	3/18/00
	В.	WAS PROTOTYPE MADE?	No
1	C.	BY WHOM MADE?	
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	LS	LOGIC - INVENT ON DISCLOSURE FORM	Disclosure N	o. 2-
	D.	WHERE CAN PROTOTYPE BE FOUND?		
5.	TEST	OF DEVICE		
	Α,	DATE		
	В.	WITNESS		
	C.	RESULT		
6.	SALE			
	A_	WAS INVENTION SOLD?	YES	NO
	В	DATE OF FIRST SALE		
7.	USE			
	A	IS THE INVENTION PRESENTLY BEING USED?	YES	NO
ļ	В.	ARE THERE SPECIFIC PLANS FOR ITS USE IN THE NEAR FUTURE?	(FES)	NO
9.	WAS	INVENTION		
	A	CONCEIVED DURING PERFORMANCE OF GOVERNMENT CONTRACT?	YES	(NO)
	B.	CONSTRUCTED DURING PERFORMANCE OF GOVERNMENT CONTRACT?	YES	<u>9</u>
	C.	TESTED DURING PERFORMANCE OF GOVERNMENT CONTRACT?	YES	NO
	D.	CONTRACT NUMBER		
10.	WAS	INVENTION		•
	Α.	CONCEIVED DURING PERFORMANCE OF CUSTOMER CONTRACT?	(ES)	NO
	В.	CONSTRUCTED DURING PERFORMANCE OF CUSTOMER CONTRACT?	YES	NO
	C.	TESTED DURING PERFORMANCE OF CUSTOMER CONTRACT?	YES	NO

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•	LS	LOGIC - INVENDEND DISCLOSURE FOR	RM Disclosure No. P-
•	D.	CUSTOMER NAME	SUN MICROSYSTEMS
THIS S SKET SHOU	DESCRII CHES, P LD FOR	PTION OF THE INVENTION SHOULD BE WRITTEN IN THE INVENTOR'S OWN WORDS PRINTS, PHOTOS AND OTHER ILLUSTRATIONS, AS WELL AS REPORTS OF ANY NA IM A PART OF THIS DISCLOSURE AND REFERENCE CAN BE MADE THERETO IN TH	S AND GENERALLY SHOULD FOLLOW THE OUTLINE GIVEN BELOW. TURE IN WHICH THE INVENTION IS REFERRED TO, IF AVAILABLE, IE DESCRIPTION OF CONSTRUCTION AND OPERATION.
	,	USE THE ATTACHED SHEETS TO ANSWER THE FO (Attach Engineering Reports or other documents	DLLOWING QUESTIONS. ation to this form.)
1.	GEN	ERAL PURPOSE OF THE INVENTION. STATE IN GENERAL TERMS THE OBJECTS OF	F THE INVENTION.
2.	DESC	CRIBE OLD METHOD(S), IF ANY, OF PERFORMING THE FUNCTION OF THE INVENTIO	DN.
з.	INDK	CATE THE DISADVANTAGES OF THE OLD METHOD(S).	*
4.	DESC	CRIBE THE CONSTRUCTION OF YOUR INVENTION, SHOWING THE CHANGES, ADDIT	TIONS AND IMPROVEMENTS OVER THE OLD METHOD.
5.	GIVE	DETAILS OF THE OPERATION IF NOT ALREADY DESCRIBED UNDER 4.	
6.	STAT	TE THE ADVANTAGES OF YOUR INVENTION OVER WHAT HAS BEEN DONE BEFORE	
7.	INDIO	CATE ANY ALTERNATE METHOD OF CONSTRUCTION.	
е.	IFAJ	IOINT INVENTION, INDICATE WHAT CONTRIBUTION WAS MADE BY EACH INVENTOR	A.
9.	FEAT	URES WHICH ARE BELIEVED TO BE NEW.	
10.	STAT	E OPINION OF RELATIVE VALUE OF THE INVENTION.	
11	AFTE	R THE DISCLOSURE IS PREPARED, IT SHOULD BE SIGNED BY THE INVENTOR(S) AT TIDED AT THE BOTTOM OF EACH SHEET.	ND THEN READ AND SIGNED BY TWO WITNESSES IN THE SPACE

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LSI LOGIC - INVENT ON DISCLOSURE FORM

Disclosure No. P-

G n ral Purpos:

The general purpose of the invention is to create a robust flip chip package design. Traditional flip chip package design involves the use of 29 mil thick silicon attached to a laminate substrate using eutectic solder bump. This kind of package design has an inherent CTE mismatch between the die (3.5 ppm) and the substrate (16 ppm) and for this reason, an adhesive material (underfill) is used to absorb th stresses on the bump due to the CTE mismatch. However, the use of underfill material has several disadvantages such as poor material adhesion between the underfill and passivation resulting in delamination of the material and subsequent cracking of the solder bumps, difficulty in filling very small gaps (driven by decrease in bump pitch), air bubbles in underfill propagate bump cracks, flux contamination of underfill material causes change in underfill properties and leads to delamination of the underfill layer, etc.

This invention proposes to eliminate CTE mismatch between the substrate and the die by first reducing the thickness of the die and then building several thin film layers of increasing CTE on the die. The thin films would have progressively increasing CTE from the die towards the substrate. This progressive CTE increase would help minimize the CTE mismatch between the individual layers and at the same time would increase the composite CTE of the die-thinfilms to that of the substrate. This increase in the composite CTE of the die-thinfilm reduces the mismatch with the substrate and hence promotes a reliable solder joint with the substrate.

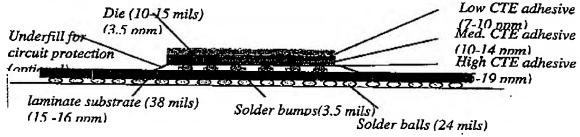
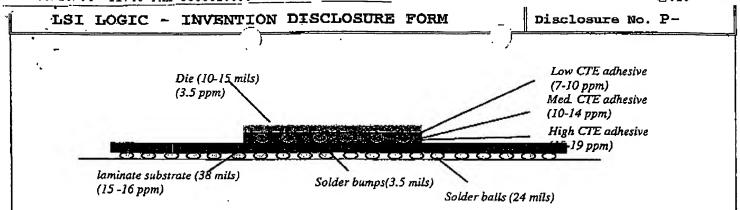


Figure 1: CTE Balanced Flipchip BGA

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Figur 2: CTE Balanced Flip Chip BGA - option 2

In option 2 shown in figure 2, the thin film layers of progressively increasing CTE are used to bond the die to the substrate. This would help minimize the CTE mismatch between the die and the substrate and increase bump fatigue life. In this construction, no underfill material is required.

Old Construction:

The old construction shown in figure 2 consists of a chip which is attached to the substrate with an underfill epoxy material filling the gap between the die and the substrate. The substrate and the die warp due to the CTE mismatch between the die and the substrate and the die-underfill interface is under residual stresses due to the CTE mismatch

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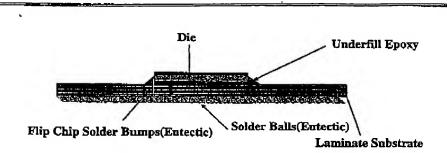


Figure 2: Old construction

LSI LOGIC

Disadvantages:

- 1. Inherent stresses in the package due to CTE mismatch between the die and the substrate
- 2. Underfill operation is required to absorb the stresses on the solder joints due to CTE mismatch.
- 3. Underfill adhesion to the die passivation and the solder mask is a concern
- 4. Underfill voids can potentially cause solder extrusions and shorting of solder bumps.

INVENT ON DISCLOSURE FORM

- 5. High flip chip bump density is difficult to achieve due to limitation of bump height and underfill gap.
- 6. For low underfill gaps, the underfill flow is inhibited by flux residues.
- 7. High flux to underfill volume ratio for low gaps causes die-underfill delamination.

Advantages of new construction:

- 1. Minimal CTE mismatch between the die and substrate
- 2. Use of underfill is optional for protection of the circuitry
- 3. Die-underfill/underfill-substrate adhesion is not critical to the functionality of the package
- 4. The CTE balancing minimizes the thermal stresses in the package and hence increases the package robustness.
- 5. Very high flip chip bump densities and lower bump pitches can be supported using this package.
- 6. The number of I/Os on the die could be increased within physical limitations.
- 7. Very large dies could be soldered on laminate substrates without any solder joint stress issues.

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Disclosure No. P-

Contribution:

Kumar Nagarajan Ideas Zafer Kutlu Ideas Shirish Shah Ideas

Value of the Invention:

The invention would help create a highly reliable flip chip package since the package is balanced in terms of stress

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